What is claimed is:

1. An apparatus for measuring a level of electro magnetic interference (EMI) with an electronic device to radiate an electromagnetic wave, the apparatus comprising:

a device for outputting a signal in response to the electromagnetic wave radiated from the electric device;

means for calculating a group_delay variation information of the device by using the signal from the device;

a processor for storing a reference group_delay variation; and

an analyzer for analyzing the level of EMI by comparing the reference group_delay variation information with the group_delay variation information.

2. The apparatus as recited in claim 1, wherein the calculating means is connected to the device.

3. The apparatus as recited in claim 1, further comprising means for absorbing the electromagnetic wave radiated from the electric device in order to protect the analyzer to be influenced from the electromagnetic wave.

4. The apparatus as recited in claim 1, wherein the analyzer computes an average and the standard deviation between the reference group_delay variation information and

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the group_delay variation information.

5. The apparatus as recited in claim 1, wherein the device is operated in high frequency.

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6. A method for measuring a level of electric magnetic interference (EMI) with an electronic device to radiate an electromagnetic wave, the method comprising the steps of:

10 a) loading a reference group_delay information of a device;

b) at the electronic device, radiating the electromagnetic wave by moving along a predetermined trace;

c) obtaining a group_delay variation information of 15 the device which is varied according to the electromagnetic wave from the electronic device at a predetermined number of detection positions on the predetermined trace; and

d) measuring an EMI level of the device by comparing the reference group_delay variation information and the 20 group_delay variation information obtained.

7. The method as recited in claim 6, wherein the step d) includes the steps of:

d1) calculating an average value of variation between 25 the loaded reference group_delay variation information and the group_delay variation information of each detection position obtained from step c) and calculating standard

deviation values of the predetermined number of detection positions based on the average value;

d2) selecting a largest value among computed standard deviation values and converting the selected standard deviation value to an electrical power value; and

d3) determining the electrical power value as an EMI level of the device.